

Learn About Atomic Force Microscopy (AFM)



Overview

The purpose of this workshop is to provide attendees first-hand knowledge on Atomic Force Microscopy (AFM). The topics to be covered are:

- Theoretical basis for Atomic Force Microscopy
- Important considerations for AFM instruments
- Applications for AFM measurements
- Hands-on measurements with model samples

Agenda

09:00-10:00	Basics of Atomic Force Microscopy Lecture
10:00-15:00	Hands-on Measurements with an AFM

When and Where

Thursday, September 13, 2018

1116 Marcus NanoTechnology Center

345 Ferst Dr NW

Atlanta, GA 30318

Register at <https://learnaboutafmatgt.eventbrite.com>

Campus Host: Dr. Walter Henderson

